



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

CONTECH RESEARCH INC.
750 Narragansett Park Drive
Rumford, RI 02916-1035
Brian MacDonald 1-401-865-6461

ELECTRICAL

Valid To: February 29, 2024

Certificate Number: 1478.02

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following tests on aerospace, aircraft, automotive, and computer components, cable assemblies, connectors, and interconnect systems; commercial and military:

<u>Test*:</u>	<u>Test Method(s) ¹:</u>
Resistance Parameters* <i>(1 to 100) ma @ 20mv DC OC, 1 ma to 600 A DC</i>	
LLCR Manual, Semi-Automatic, and Automatic	EIA 364 TP 23; MIL-STD-1344, Method 3002 ² ; MIL-DTL-55302; IEC 60512-2-1; USB 2.0, 3.0; SAE/USCAR-2; SAE/USCAR-30; SAE J2030
Contact Resistance	EIA 364 TP 06; MIL-STD-1344, Method 3004 ² ; MIL-STD-202, Method 307; IEC 60512-2-2; SAE J2030
Voltage Drop	SAE/USCAR-2; SAE J2030
Shell-To-Shell and Shell-To-Bulkhead Resistance	EIA 364, TP 83; MIL-STD-1344, Method 3007 ² ; IEC 60512-02-6
Rise Time Degradation	EIA 364 TP 102; MIL-PRF-49142 (par. 3.25 / 4.6.22)

<u>Test*:</u>	<u>Test Method(s) ¹:</u>
RF Hi Pot Withstanding Voltage	MIL-PRF-39012; MIL-PRF-49142 (par. 3.21 / 4.6.18)
Parameters* <i>1 KHz to 1 GHz</i>	
Inductance	EIA 364 TP 33, TP 69
Capacitance	EIA 364 TP 30; MIL-STD-202, Method 305; IEC 60512-22-1; USB 2.0, 3.0
Detection Parameters* <i>1ns, 10 ns, 50ns, 0.1µs, 1 µs, 10µs</i>	
Low Nanosecond Event Detection	EIA 364 TP 87
Discontinuity Event Detection	EIA 364 TP 46; MIL-STD-202, Method 310; IEC 60512-2-5; SAE J2030
DWV Parameters* <i>(100 V 6,000 VAC, 10 mbars)</i>	
DWV Sea Level	EIA3 64 TP 20; MIL-STD-1344, Method 3001 ² ; MIL-STD-202, Method 301; UL 1977; IEC 60512-4-1; USB 2.0, 3.0
DWV Altitude	EIA 364 TP 20; IEC 60512-4-1
IR Parameters* <i>(100 to 6,000) V DC, 50,000 MΩ Max</i>	
Insulation Resistance	EIA 364 TP 21; MIL-STD-1344, Method 3003 ² ; MIL-STD-202, Method 302; IEC 60512-3-1; USB 2.0, 3.0; SAE/USCAR-2; SAE/USCAR-30; SAE J2030

<u>Test*:</u>	<u>Test Method(s) ¹:</u>
Parameters* <i>100 mA to 600A DC</i>	
Current Cycling	EIA 364 TP 55; IEC 60512-9-5; SAE/USCAR-2; SAE J2030
Temperature Rise	EIA 364 TP 70; UL1977; IEC 60512-5-1; SAE/USCAR-2; SAE J2030
Parameters* <i>100 mA to 600A DC, (1 to 100) V DC</i>	
Current Overload (Hot Swap)	UL 1977
Resistance to Arcing (<i>DC Tests Only</i>)	UL 1977
Magnetic Permeability	EIA-364-TP-54; MIL-STD-1344, Method 3006 ²

*Also using customer specific test methods utilizing any combination of test equipment parameters listed above.

¹ When the date, edition, version, etc. is not identified in the scope of accreditation, laboratories may use the version that immediately precedes the current version for a period of one year from the date of publication of the standard measurement method, per part C., Section 1 of A2LA R101 - *General Requirements-Accreditation of ISO-IEC 17025 Laboratories*.

² NOTE: This laboratory's scope contains withdrawn or superseded methods. As a clarifier, this indicates that the applicable method itself has been withdrawn or is now considered "historical" and not that the laboratory's accreditation for the method has been withdrawn.



Accredited Laboratory

A2LA has accredited

CONTECH RESEARCH INC.

Rumford, RI

for technical competence in the field of

Electrical Testing

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017 *General requirements for the competence of testing and calibration laboratories*. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



Presented this 10th day of January 2022.

A blue ink signature of the Vice President of Accreditation Services.

Vice President, Accreditation Services
For the Accreditation Council
Certificate Number 1478.02
Valid to February 29, 2024

For the types of tests to which this accreditation applies, please refer to the laboratory's Electrical Scope of Accreditation.